

I THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Henry F. Erk, et al. Serial No. 10/665,982 Filed September 18, 2003 Confirmation No. 5374 For PROCESS FOR ETCHING SILICON WAFERS Art Unit 1763

January 21, 2004

COMMISSIONER FOR PATENTS P.O. BOX 1450 ALEXANDRIA, VIRGINIA 22313-1450

SIR:

## INFORMATION DISCLOSURE STATEMENT

In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit the attached PTO/SB/08A for consideration by the Patent and Trademark Office in the above-entitled application and to be made of record therein.

In accordance with the Pre-OG notice of July 11, 2003 partially waiving the requirements of 37 C.F.R. 1.98(a)(2)(i), copies of the U.S. patent documents are not supplied. Applicants submit herewith a copy of a foreign patent document (Cite No. 22) and a literature reference (Cite No. 23). In accordance with 37 C.F.R. §1.98(a) and MPEP 609, an English language translation of Cite No. 22 is being provided. Thus, a concise explanation of the relevance of this reference is not being provided.

This Information Disclosure Statement is being submitted pursuant to 37 C.F.R. §1.97(b) in that applicants believe that it is being filed prior to the mailing date of the first Office action on the merits. Accordingly, neither a statement nor fee

MEMC 02-0051(3032.1) PATENT

under 37 C.F.R. §1.97(c) or (d) is required. However, if applicants are mistaken and an Office Action was issued prior to the date of mailing of this Statement, the Commissioner is hereby authorized to charge any fees incurred regarding this Information Disclosure Statement to Account No. 19-1345.

Respectfully submitted,

Andrew C. Wegman, Reg. No. 54,530 SENNIGER, POWERS, LEAVITT & ROEDEL

One Metropolitan Square, 16th Floor

St. Louis, Missouri 63102

(314) 231-5400

ACW/dfw \*Attachment

Express Mail Label No. EV 416449212 US

PTO/SB/0	8A			Complete if Known		
INF	ORMATION DI	ISCI	LOSURE	Application Number	10/665,982	
STATEMENT BY APPLICANT				Filing Date	September 18, 2003	
(use a	is many cheets	as	necessary)	Confirmation Number	5374	
	OIRE S			First Named Inventor	Henry Erk	
. (	JAH 2 1 2004 E			Group Art Unit	1763	
The second secon				Examiner Name	Not Yet Assigned	
Sheet	9 1929	of	2	Attorney Docket No.	MEMC 02-0051(3032.1)	

	U.S. PATENT DOCUMENTS						
Examiner	Cite	U.S. Patent D	ocument	No. of Detector of April 2014	Date of Publication of Cited		
Initials* No.1	Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Document MM-DD-YYYY			
	1.	2,902,419		J.I. Carasso et al.	09-01-1959		
	2.	4,056,413		Masayoshi Yoshimura	11-01-1977		
	3.	4,781,853		Robert K. Lowry et al.	11-01-1988		
	4.	4,859,280		Robert K. Lowry et al.	08-22-1989		
	5.	5,756,399		Hirofumi Hajime et al.	05-26-1998		
	6.	5,804,090		Yasukazu lwasaki et al.	09-08-1998		
	7.	5,849,636		Takamitsu Harada et al.	12-15-1998		
	8.	5,866,266		Atsunori Takasu	02-02-1999		
	9.	5,891,353		Hisashi Masumura et al.	04-06-1999		
	10.	5,963,871		Ying Zhinong et al.	10-05-1999		
	11.	5,972,236		Hiroshi Tanaka et al.	10-26-1999		
	12.	5,976,983		Seiichi Miyazaki et al.	11-02-1999		
	13.	6,043,156		Fumitaka Kai et al.	03-28-2000		
	14.	6,099,748		Shigeyoshi Netsu et al.	08-08-2000		
	15.	6,110,839		Masami Nakano et al.	08-29-2000		
	16.	6,319,845	B1	Isao Uchiyama et al.	11-20-2001		
	17.	6,346,485	B1	Takashi Nihonmatsu et al.	02-12-2002		

Examiner	Date		
Signature	Considered		

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵Applicant is to place a check mark here if English language Translation is attached or place an "A" here if English language abstract is attached..

PTO/SB/08A	Complete if Known		
INFORMATION DISCLOSURE	Application Number	10/665,982	
STATEMENT BY APPLICANT	Filing Date	September 18, 2003	
(use as many sheets as necessary)	Confirmation Number	5374	
OIPE	First Named Inventor	Henry Erk	
JAN 2 1 2005	Group Art Unit	1763	
	Examiner Name	Not Yet Assigned	
Sheet of 2	Attorney Docket No.	MEMC 02-0051(3032.1)	

18.	6,355,121	B1	Sugarna M. Onalka et al	00.40.0000
	0,000,121	[ 0 ]	Susanne M. Opalka et al.	03-12-2002
 19.	6,376,335	B1	David Zhang et al.	04-23-2002
 20.	6,394,106	B1	Michael Jolley	05-28-2002
21.	6,432,837	B2	Takashi Nihonmatsu et al.	08-13-2002

Eveminer	Cito	Foreign Patent Document			Name of Detentor or Applicant of	Date of Publication of	
Examiner Initials*	Cite No. <sup>1</sup>	Office	Number⁴	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	
	22.	PCT	WO 02/35593	A1	Shin-Etsu Handotai Co., Ltd.	05-02-2002	√

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS							
Examiner Cite No.1		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	L <sub>e</sub>				
	23.	PALIK, E.D. and GLEMBOCKI, O.J., "Etching roughness for (100) silicon surfaces in aqueous KOH", J. Appl. Phys., 70 (6), 15 Sept. 1991, 3291-3300					

Examiner	Date	
Signature	Considered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

C)

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵Applicant is to place a check mark here if English language Translation is attached or place an "A" here if English language abstract is attached..